

## EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
L14	0	(semiconductor integrated circuit AND scan test operation AND two blocks AND performing active function AND isolation unit AND input terminal AND scan clock input AND overlapping pulses AND phase different AND system clock AND scan clock).clm.	US-PGPUB; USPAT; USOCR	ADJ	ON	2008/03/02 23:26

3/ 2/ 08 11:27:58 PM

C:\Documents and Settings\pchung\My Documents\EAST\Workspaces\10763255.wsp